

**Search Notes****Application/Control No.**

10/805,890

**Examiner**

Binh X. Tran

**Applicant(s)/Patent under Reexamination**

NALLAN ET AL.

**Art Unit**

1765

**SEARCHED**

Class	Subclass	Date	Examiner
216	58	11/9/2005	BT
216	67	11/9/2005	BT
216	68	11/9/2005	BT
438	722	11/9/2005	BT

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search keywords and inventors' name using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	11/9/2005	BT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner